

Power MOSFET

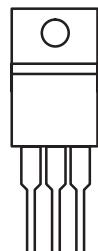
PRODUCT SUMMARY		
V _{DS} (V)	200	
R _{DS(on)} (Ω)	V _{GS} = 10 V	0.20
Q _g max. (nC)	70	
Q _{gs} (nC)	13	
Q _{gd} (nC)	39	
Configuration	Single	

FEATURES

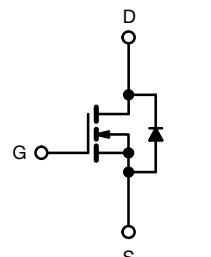
- Surface mount
- Low-profile through-hole
- Available in tape and reel
- Dynamic dV/dt rating
- 150 °C operating temperature
- Fast switching
- Fully avalanche rated



TO-220AB



DRAIN connected to TAB

G D S
Top View

N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)				
PARAMETER		SYMBOL	LIMIT	UNIT
Drain-Source Voltage		V _{DS}	200	
Gate-Source Voltage		V _{GS}	± 20	V
Continuous Drain Current	V _{GS} at 10 V	I _D	14	
	T _C = 25 °C		10	A
	T _C = 100 °C			
Pulsed Drain Current ^{a, e}		I _{DM}	56	
Linear Derating Factor			1.0	W/°C
Single Pulse Avalanche Energy ^{b, e}		E _{AS}	580	mJ
Avalanche Current ^a		I _{AR}	15	A
Repetitive Avalanche Energy ^a		E _{AR}	13	mJ
Maximum Power Dissipation	T _C = 25 °C	P _D	110	
	T _A = 25 °C		3.1	W
Peak Diode Recovery dV/dt ^{c, e}		dV/dt	5.0	V/ns
Operating Junction and Storage Temperature Range		T _J , T _{stg}	-55 to +150	°C
Soldering Recommendations (Peak temperature) ^d	for 10 s		300	

Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- V_{DD} = 50 V, starting T_J = 25 °C, L = 2.7 mH, R_g = 25 Ω, I_{AS} = 18 A (see fig. 12).
- I_{SD} ≤ 18 A, dI/dt ≤ 150 A/μs, V_{DD} ≤ V_{DS}, T_J ≤ 150 °C.
- 1.6 mm from case.
- Uses IRF640, SiHF640 data and test conditions.

THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient (PCB mounted, steady-state) ^a	R _{thJA}	-	40	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	1.0	

Note

- a. When mounted on 1" square PCB (FR-4 or G-10 material).

SPECIFICATIONS ($T_J = 25^\circ\text{C}$, unless otherwise noted)								
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static								
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}$, $I_D = 250 \mu\text{A}$		200	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to 25°C , $I_D = 1 \text{ mA}$ ^c		-	0.29	-	V/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$		1.0	-	3.0	V	
Gate-Source Leakage	I _{GSS}	$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 200 \text{ V}$, $V_{GS} = 0 \text{ V}$		-	-	25	μA	
		$V_{DS} = 160 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = 125^\circ\text{C}$		-	-	250		
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 11 A ^b	-	0.20	-	Ω	
Forward Transconductance	g _{fs}	$V_{DS} = 50 \text{ V}$, $I_D = 11 \text{ A}$ ^d		6.7	-	-	S	
Dynamic								
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, f = 1.0 MHz, see fig. 5 ^d		-	1300	-	pF	
Output Capacitance	C _{oss}			-	430	-		
Reverse Transfer Capacitance	C _{rss}			-	130	-		
Total Gate Charge	Q _g	V _{GS} = 10 V	I _D = 18 A, V _{DS} = 160 V, see fig. 6 and 13 ^{b, c}	-	-	70	nC	
Gate-Source Charge	Q _{gs}			-	-	13		
Gate-Drain Charge	Q _{gd}			-	-	39		
Turn-On Delay Time	t _{d(on)}			-	14	-		
Rise Time	t _r	V _{DD} = 100 V, I _D = 18 A, R _g = 9.1 Ω, R _D = 5.4 Ω, see fig. 10 ^{b, c}		-	51	-	ns	
Turn-Off Delay Time	t _{d(off)}			-	45	-		
Fall Time	t _f			-	36	-		
Gate Input Resistance	R _g	f = 1 MHz, open drain		0.5	-	3.6	Ω	
Drain-Source Body Diode Characteristics								
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	18	A	
Pulsed Diode Forward Current ^a	I _{SM}			-	-	72		
Body Diode Voltage	V _{SD}	$T_J = 25^\circ\text{C}$, I _S = 18 A, V _{GS} = 0 V ^b		-	-	2.0	V	
Body Diode Reverse Recovery Time	t _{rr}	$T_J = 25^\circ\text{C}$, I _F = 18 A, dI/dt = 100 A/μs ^{b, c}		-	300	610	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			-	3.4	7.1	μC	
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _D)						

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width ≤ 300 μs; duty cycle ≤ 2 %.
c. Uses IRF640/SiHF640 data and test conditions.

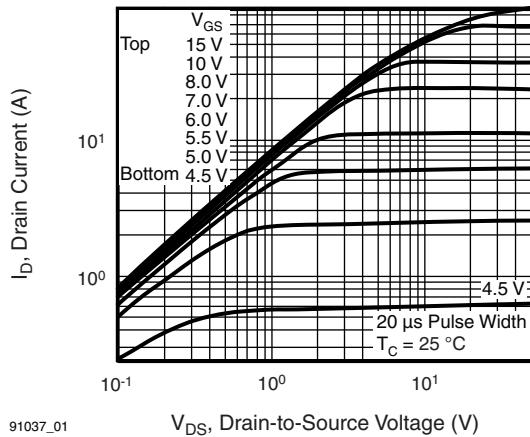
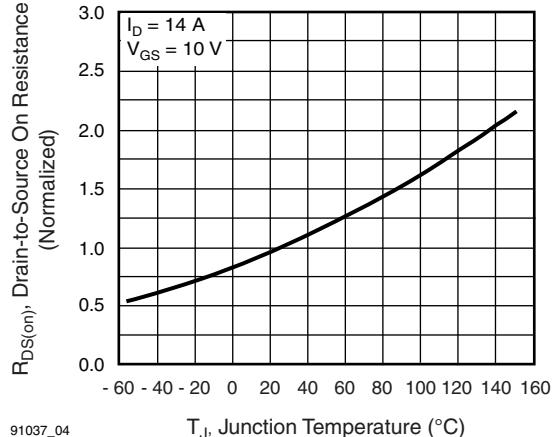
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)Fig. 1 - Typical Output Characteristics, $T_J = 25$ °C

Fig. 4 - Normalized On-Resistance vs. Temperature

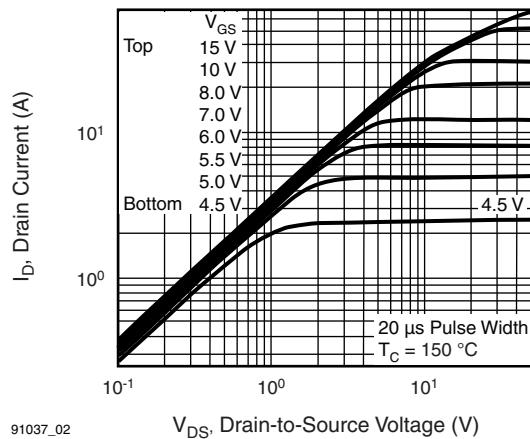
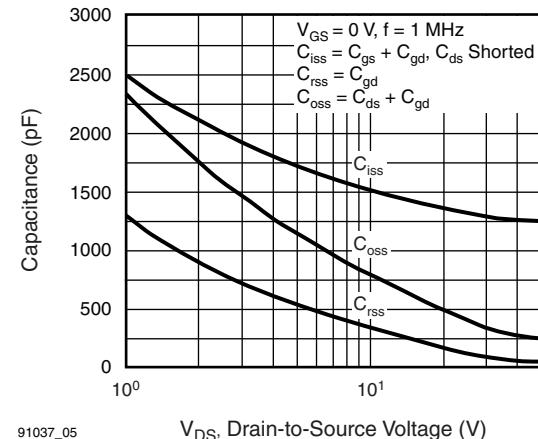
Fig. 2 - Typical Output Characteristics, $T_J = 175$ °C

Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

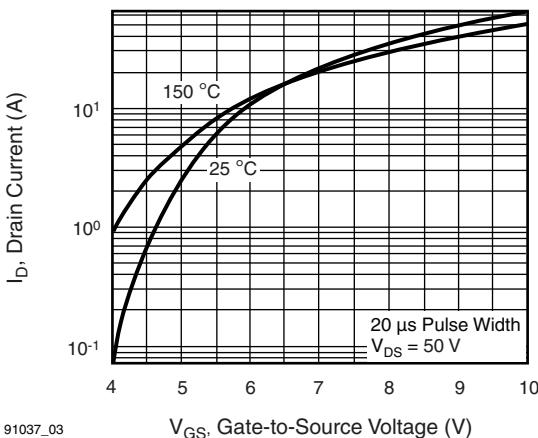


Fig. 3 - Typical Transfer Characteristics

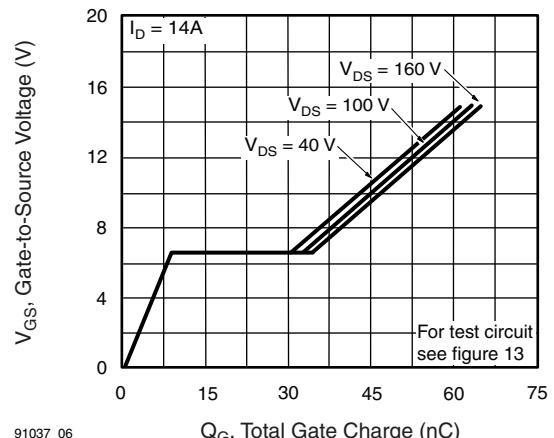


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

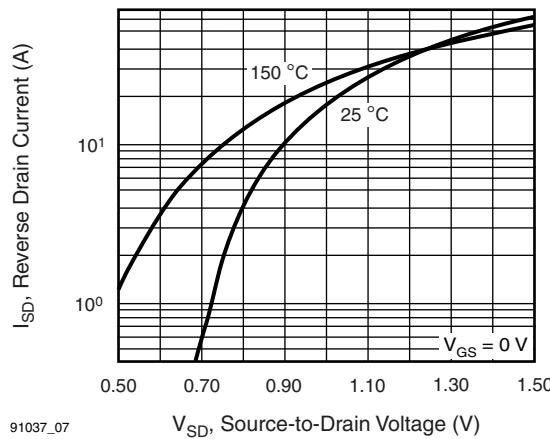


Fig. 7 - Typical Source-Drain Diode Forward Voltage

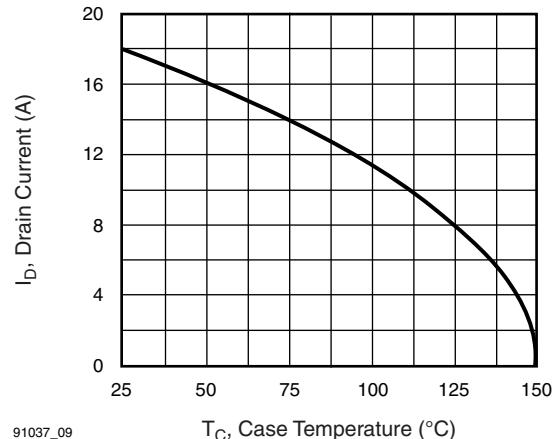


Fig. 9 - Maximum Drain Current vs. Case Temperature

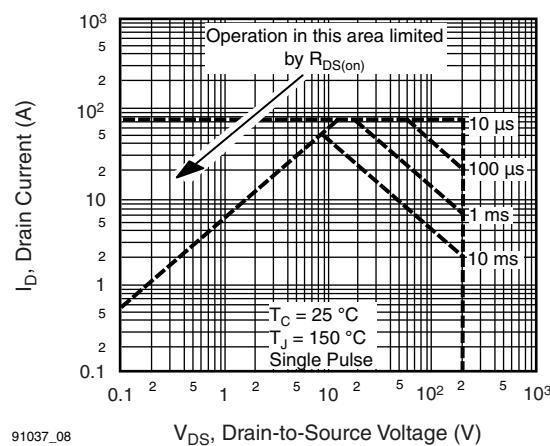


Fig. 8 - Maximum Safe Operating Area

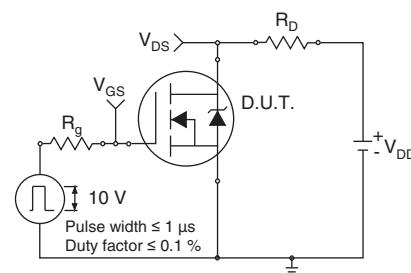


Fig. 10a - Switching Time Test Circuit

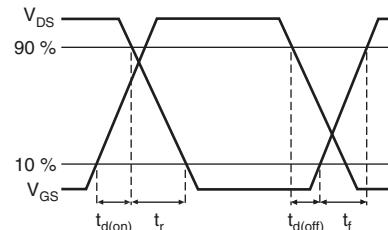


Fig. 10b - Switching Time Waveforms

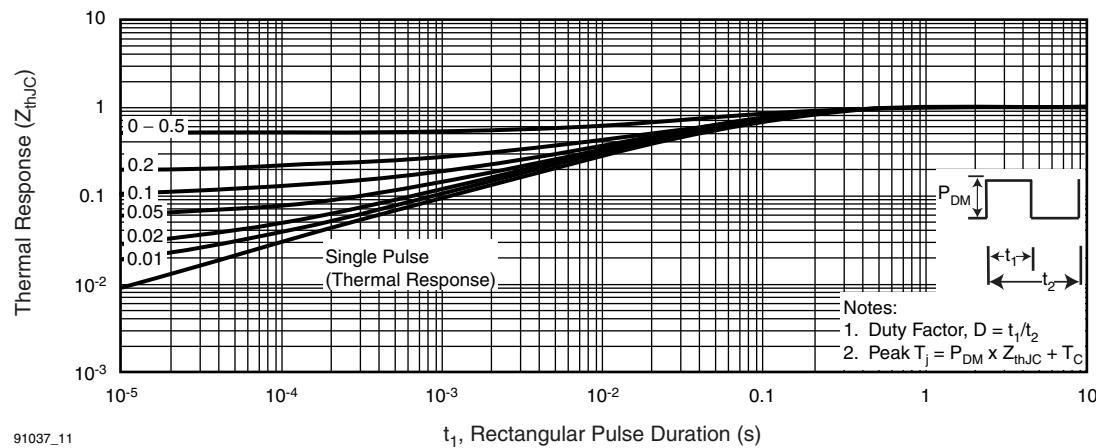


Fig. 10 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

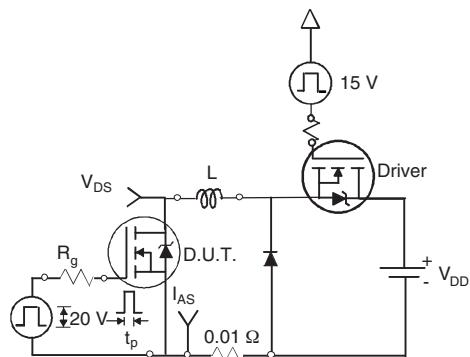


Fig. 12a - Unclamped Inductive Test Circuit

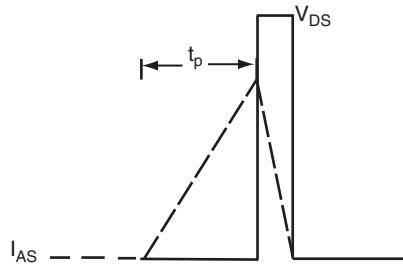


Fig. 12b - Unclamped Inductive Waveforms

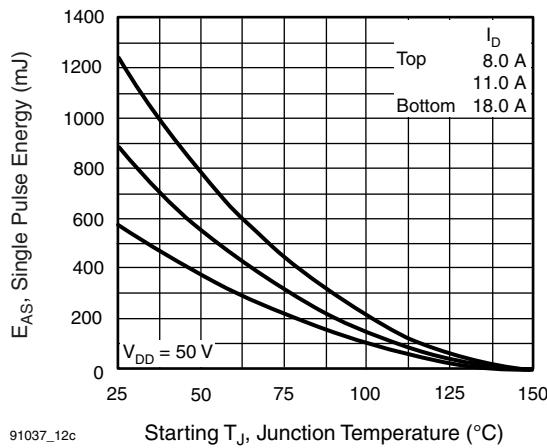


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

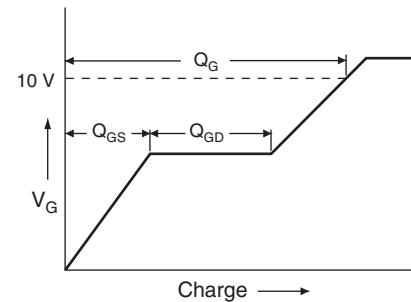


Fig. 13a - Basic Gate Charge Waveform

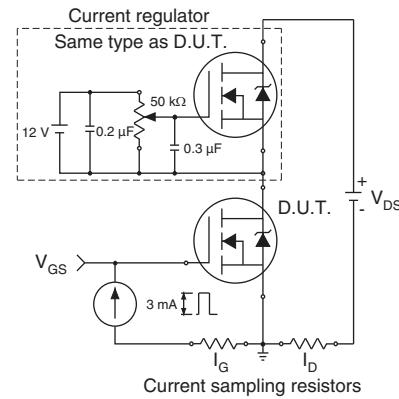
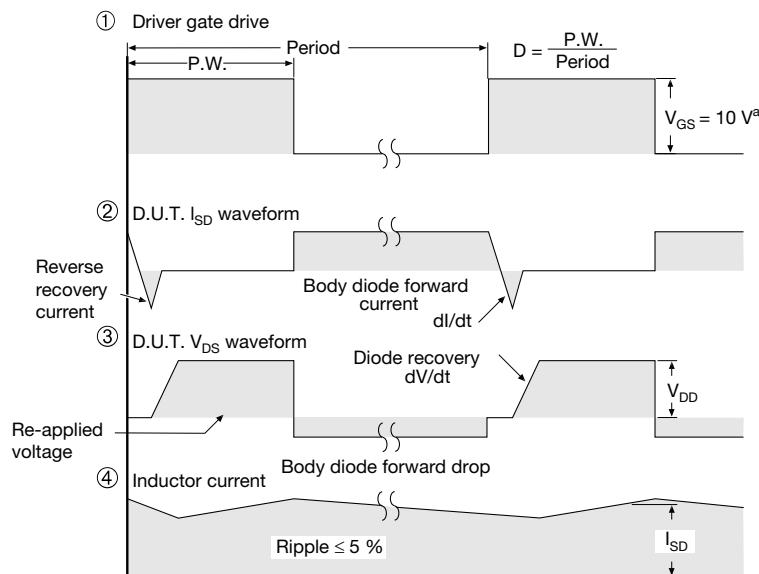
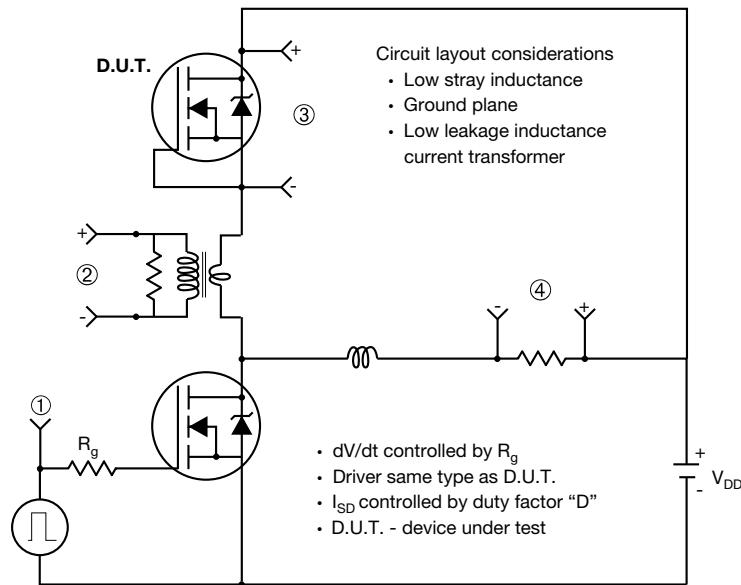


Fig. 13b - Gate Charge Test Circuit

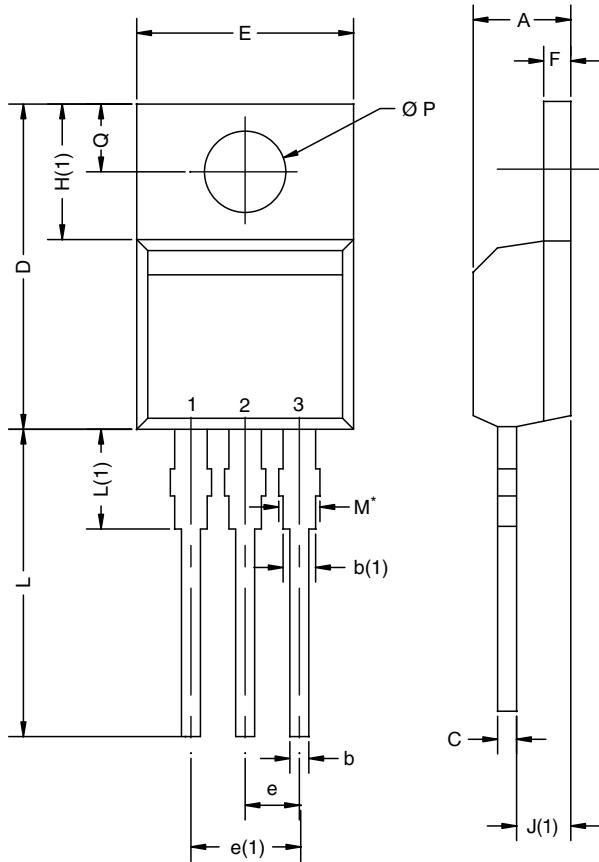
Peak Diode Recovery dV/dt Test Circuit


Note

a. $V_{GS} = 5 \text{ V}$ for logic level devices

Fig. 14 - For N-Channel

TO-220AB

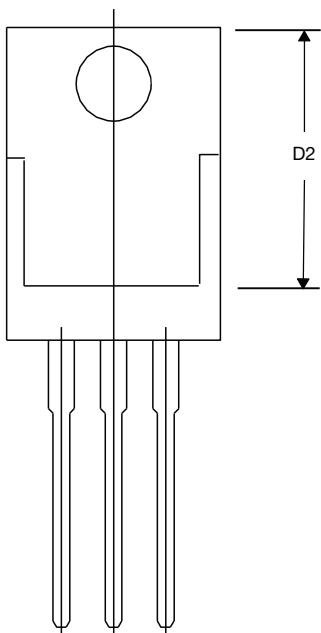


DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	4.25	4.65	0.167	0.183
b	0.69	1.01	0.027	0.040
b(1)	1.20	1.73	0.047	0.068
c	0.36	0.61	0.014	0.024
D	14.85	15.49	0.585	0.610
D2	12.19	12.70	0.480	0.500
E	10.04	10.51	0.395	0.414
e	2.41	2.67	0.095	0.105
e(1)	4.88	5.28	0.192	0.208
F	1.14	1.40	0.045	0.055
H(1)	6.09	6.48	0.240	0.255
J(1)	2.41	2.92	0.095	0.115
L	13.35	14.02	0.526	0.552
L(1)	3.32	3.82	0.131	0.150
Ø P	3.54	3.94	0.139	0.155
Q	2.60	3.00	0.102	0.118

ECN: T14-0413-Rev. P, 16-Jun-14
DWG: 5471

Note

* M = 1.32 mm to 1.62 mm (dimension including protrusion)
Heatsink hole for HVM



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